January 1999

# SEMICONDUCTOR TM

# NDS9933A Dual P-Channel Enhancement Mode Field Effect Transistor

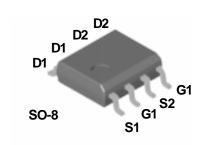
## **General Description**

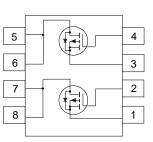
This P-Channel enhancement mode power field effect transistor is produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance.

These devices are particularly suited for low voltage aplications such as DC motor control and DC/DC conversion where fast switching,low in-line power loss, and resistance to transients are needed.

# Features

- -2.8 A, -20 V.  $R_{DS(on)} = 0.14 \Omega @ V_{GS} = -4.5 V$  $R_{DS(on)} = 0.19 \Omega @ V_{GS} = -2.7 V$  $R_{DS(on)} = 0.20 \Omega @ V_{GS} = -2.5 V.$
- High density cell design for extremely low R<sub>DS(on)</sub>.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.





# Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		NDS9933A	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		<u>+</u> 8	V
ID	Drain Current - Continuous	(Note 1a)	-2.8	А
	- Pulsed		-10	
PD	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range		-55 to +150	۰C

# **Thermal Characteristics**

$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R <sub>θ</sub> ιc	Thermal Resistance, Junction-to-Case	(Note 1)	40	∘C/W

# Package Outlines and Ordering Information

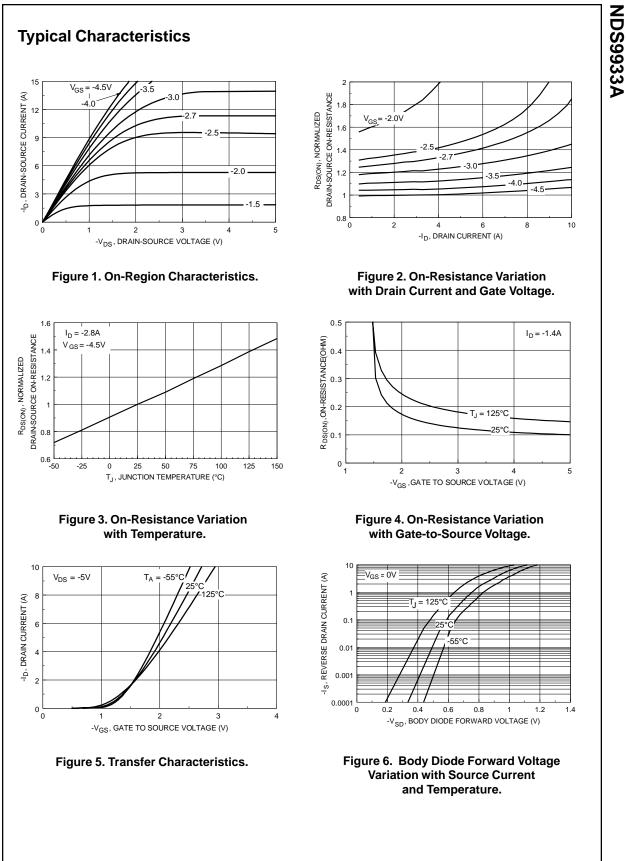
Device Marking	Device	Reel Size	Tape Width	Quantity
NDS9933A	NDS9933A	13"	12mm	2500 units

BV <sub>DSS</sub> <u>BV<sub>DSS</sub></u> ΔT <sub>J</sub> DSS	acteristics Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	$V_{GS} = 0 \text{ V}, \text{ I}_D = -250 \mu\text{A}$ I <sub>D</sub> = -250 \mu\$A, Referenced to 25°C	-20			
BV <u>DSS</u> ΔTJ DSS	Breakdown Voltage Temperature Coefficient		-20	<b>I</b>		
<u>BVdss</u> ΔTj dss gssf	Coefficient	$I_D$ = -250 $\mu$ A, Referenced to 25°C				V
	Zero Gate Voltage Drain Current			-25		mV/°C
GSSF	Zere Gate Voltage Brain Garrent	$V_{DS} = -16 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			-1	μA
	Gate-Body Leakage Current, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
GSSR	Gate-Body Leakage Current, Reverse	$V_{GS}$ = -8 V, $V_{DS}$ = 0 V			-100	nA
On Chara	acteristics (Note 2)					
/ <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	-0.4	-0.65	-1	V
<u>ΔVgs(th)</u> ΔTj	Gate Threshold Voltage Temperature Coefficient	$I_D$ = -250 µA, Referenced to 25°C		4		mV/°C
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	$ \begin{array}{l} V_{GS}=-4.5 \; V, \; I_{D}=-2.8 \; A \\ V_{GS}=-4.5 \; V, \; I_{D}=-2.8 A, T_{J}=125^{\circ}C \\ V_{GS}=-2.7 \; V, \; I_{D}=-1.5 \; A \\ V_{GS}=-2.5 \; V, \; I_{D}=-1.5 \; A \end{array} $		0.10 5 0.15 0 0.13 5 0.14 0	0.140 0.240 0.190 0.200	Ω
D(on)	On-State Drain Current	V <sub>GS</sub> = -4.5 V, V <sub>DS</sub> = -5 V	-10	0		А
JFS	Forward Transconductance	V <sub>DS</sub> = -5 V, I <sub>D</sub> = -2.8 A		6.5		S
Dynamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = -10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$		405		pF
Coss	Output Capacitance	f = 1.0 MHz		170		pF
Crss	Reverse Transfer Capacitance			45		pF
Switchin	g Characteristics (Note 2)					
d(on)	Turn-On Delay Time	$V_{DD} = -5 V, I_D = -1 A,$		6.5	13	ns
r	Turn-On Rise Time	$V_{GS}$ = -4.5 V, $R_{GEN}$ = 6 $\Omega$		20	35	ns
d(off)	Turn-Off Delay Time			31	50	ns
f	Turn-Off Fall Time	1		21	35	ns
λ <sup>g</sup>	Total Gate Charge	$V_{DS} = -5 V, I_D = -2.8 A,$		6	8.5	nC
λ <sub>gs</sub>	Gate-Source Charge	$V_{GS} = -4.5 V,$		0.8		nC
λ <sub>gd</sub>	Gate-Drain Charge			1.3		nC
	urce Diode Characteristics and	d Maximum Ratings				
Drain-So					-1.3	Α
S Drain-So	Maximum Continuous Drain-Source Did	bde Forward Current			-1.2	V

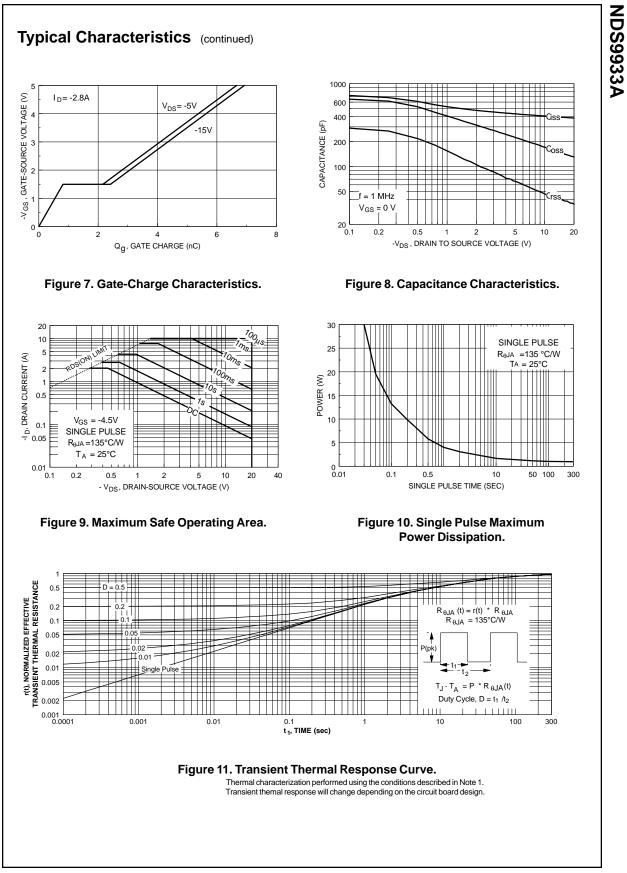
NDS9933A

2: Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%

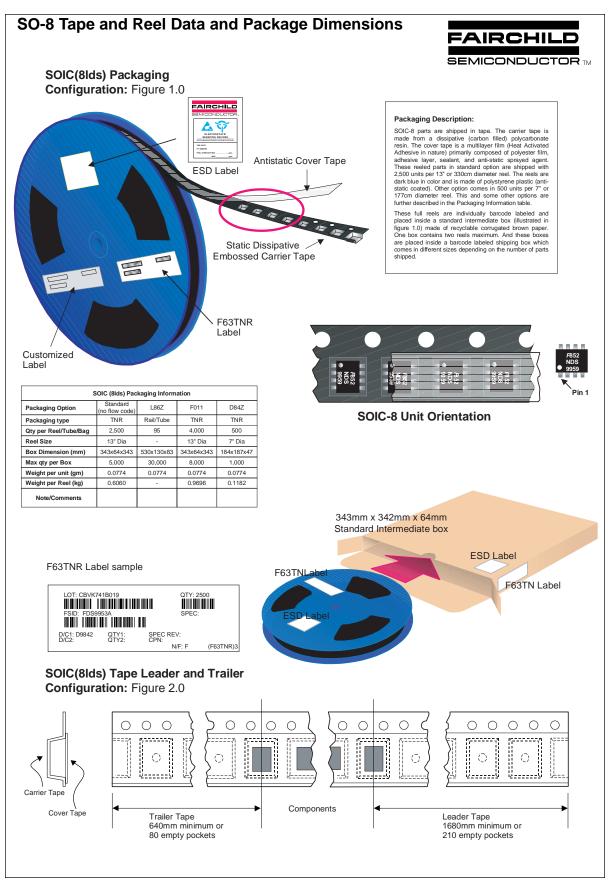
Scale 1 : 1 on letter size paper



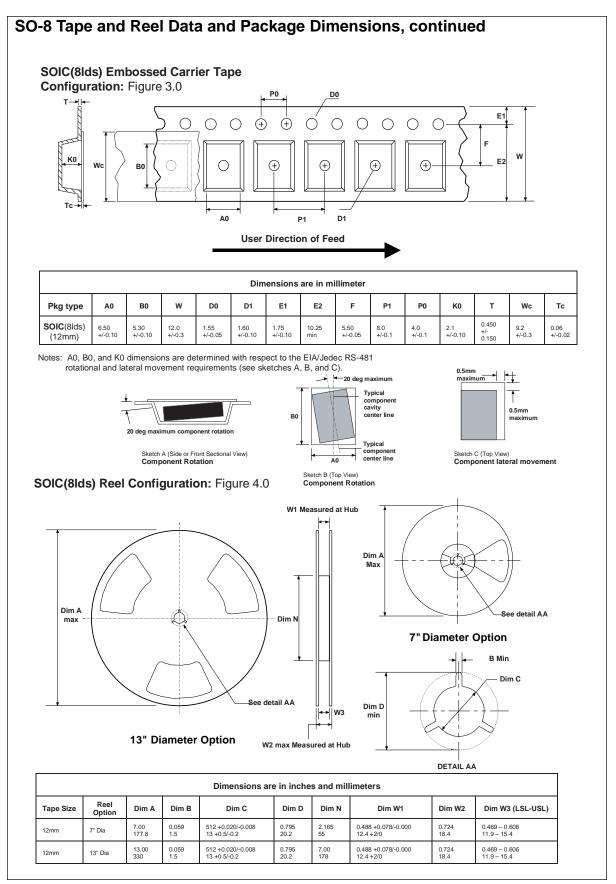
NDS9933A Rev. A

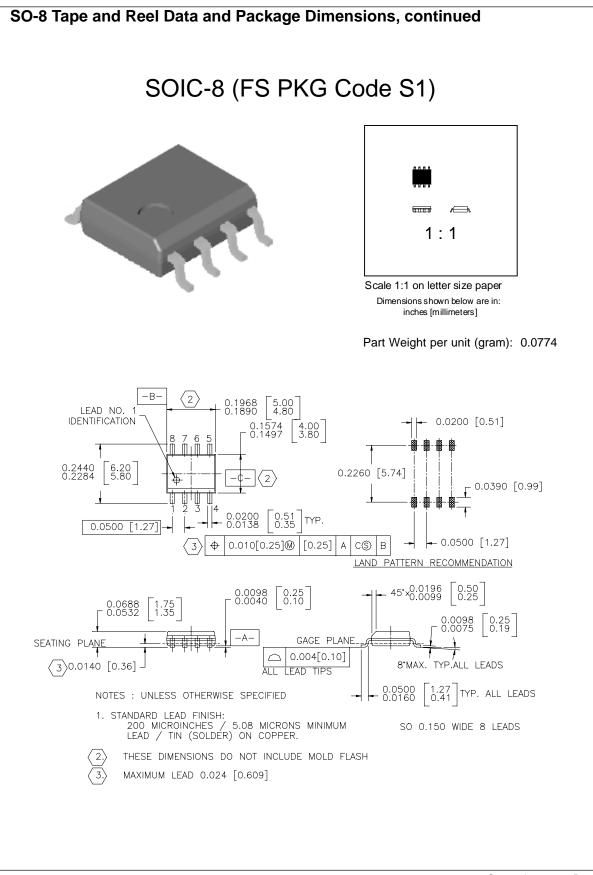


NDS9933A Rev. A



July 1999, Rev. B





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